

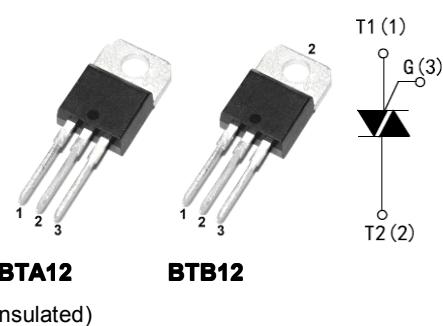
## **BTA/BTB12**

### **12A TRIACS**

#### Description

- Package: TO-220T
- Available either in through-hole or surface-mount packages, the BTA/BTB12 is suitable for general purpose AC switching. They can be used as an ON/OFF function in application such as static relays, heating regulation ,Induction motor starting circuits...or for phase control operation in light dimmers, motor speed controllers.

#### DRAWING



#### Absolute Maximum Ratings

Symbol	Parameter	Value	Unit
$I_{TRMS}$	RMS on-state current(full sine wave)	TO-220T TO-220T Ins.	TC=105°C TC=90°C
$I_{TSM}$	Non repetitive surge peak on-state current(full cycle, $T_j$ initial=25°C)	F=50Hz F=60Hz	t=20ms t=16.7ms
$I^2t$	$I^2t$ Value for fusing	tp=10ms	78
DI/DT	Critical rate of rise of on-state current $IG=2X_{IGT,tr\leq 100ns}$	F=120Hz	$T_j=125^\circ C$
VDSM/V RSM	Non repetitive surge peak off-state voltage	tp=10ms	$T_j=25^\circ C$
IGM	Peak gate current	tp=20us	$T_j=125^\circ C$
			4
$P_{G(AV)}$	Average gate power dissipation	$T_j=125^\circ C$	1
$T_{stg}$ $T_j$	Storage junction temperature range		-40 to +150
	Operating junction temperature range		-40 to +125

#### Electrical Characteristics ( $T_j=25^\circ C$ ,unless otherwise specified)

#### Snubberless™ and Logic Level(3 quadrant)

Symbol	Test conditions	Quadrant	<b>BTA12</b>		Unit
$I_{GT}(1)$	$V_D=12V$ $R_L=30\Omega$	I - II - III	MAX	50	mA
$V_{GT}$		I - II - III	MAX	1.3	V
$V_{GD}$	$V_D=V_{DRM}$ $R_L=3.3K\Omega$ $T_j=125^\circ C$	I - II - III	MIN	0.2	V
$IH(2)$	IT=100mA		MAX	50	mA
$IL$	$I_G=1.2I_{GT}$	I - III	MAX	70	mA
		II		80	
$Dv / Dt(2)$	$VD=67\%V_{DRM}$ Gate open $T_j=125^\circ C$		MIN	1000	V/us
$(Di/dt)c(2)$	$(Dv/dt)c=0.1 V/us$ $T_j=125^\circ C$	MIN	-	A/ms	
	$(Dv/dt)c=10V/us$ $T_j=125^\circ C$		-		
	Without snubber $T_j=125^\circ C$		12		

**Standard (4 Quadrants)**

<b>Symbol</b>	<b>Test conditions</b>	<b>Quadrant</b>	<b>BTA12</b>		<b>Unit</b>
IGT(1)	VD=12V RL=30Ω	I - II-III IV	MAX	50 100	mA
VGT		ALL		1.3	
VGD	VD=VDRM RL=3.3KΩ Tj=125°C	ALL	MIN	0.2	V
IH(2)	IT=500mA	I -III- IV II	MAX	50 100	mA
IL	IG=1.2IGT			50	
(DI/dt)(2)	VD=67%VDRM Gate open Tj=125°C		MIN	400	V/us
(DI/dt)c(2)	(Dv/dt)c=5.3 A/ms Tj=125°C		MIN	10	V/us

**Static Characteristics**

<b>Symbol</b>	<b>Test conditions</b>			<b>Value</b>	<b>Unit</b>
VTM(2)	ITM=11A tp=380us	TJ=25°C	MAX	1.55	V
Vto(2)	Threshold voltage	TJ=125°C	MAX	0.85	V
Rd(2)	Dynamic resistance	TJ=125°C	MAX	35	mΩ
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>DRM</sub> =V <sub>RRM</sub>	TJ=25°C	MAX	5	uA
		TJ=125°C		1	mA
V <sub>DRM</sub> /V <sub>RRM</sub>	Voltage	TJ=25°C	MIN	600 and 800	V

**Note 1:** minimum IGT is guaranteed at 5% of IGT max

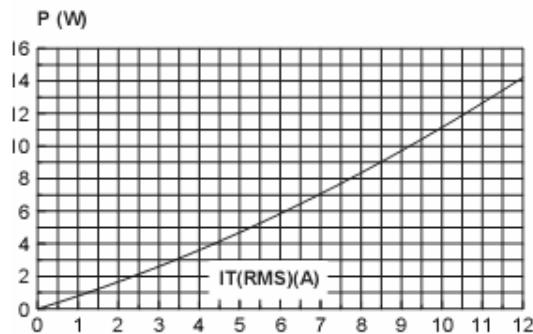
**Note 2:** for both polarities of A2 referenced to A1

**Thermal Resistances**

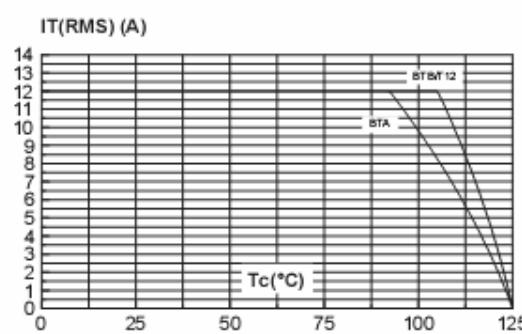
<b>Symbol</b>	<b>Parameter</b>	<b>Value</b>	<b>Unit</b>
R <sub>th(j-c)</sub>	Junction to case(AC)	TO-220T	1.4
		TO-220T(Insulated)	2.3
R <sub>th(j-a)</sub>	Junction to ambient	TO-220T/ TO-220T(Insulated)	60

**Typical Characteristics**

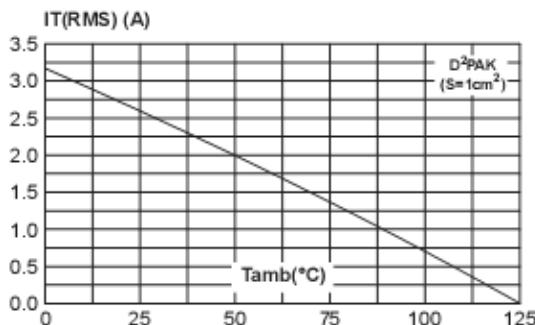
**Fig. 1:** Maximum power dissipation versus RMS on-state current (full cycle).



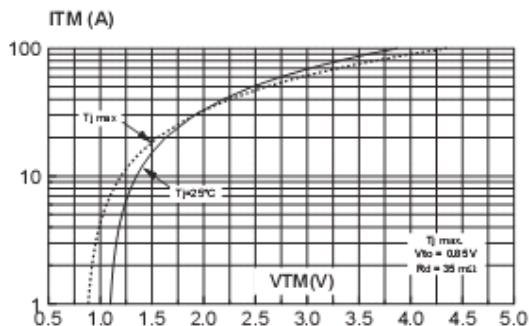
**Fig. 2-1:** RMS on-state current versus case temperature (full cycle).



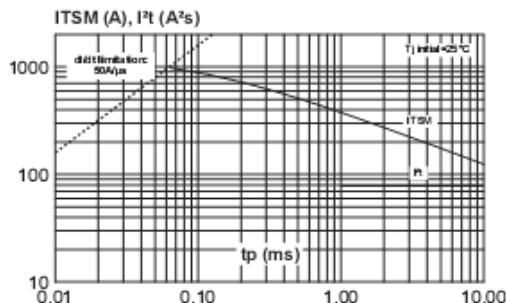
**Fig. 2-2:** RMS on-state current versus ambient temperature (printed circuit board FR4, copper thickness: 35 $\mu$ m), full cycle.



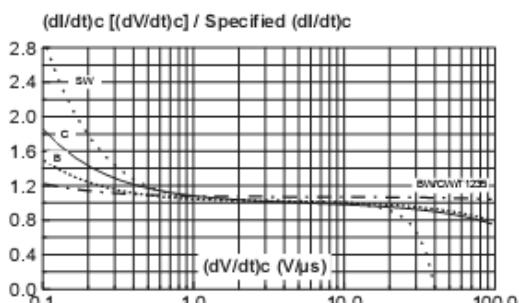
**Fig. 4:** On-state characteristics (maximum values).



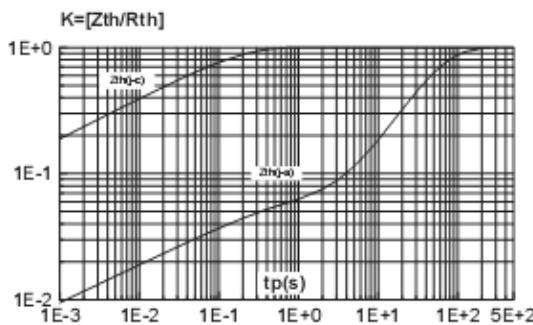
**Fig. 6:** Non-repetitive surge peak on-state current for a sinusoidal pulse with width  $t_p < 10ms$ , and corresponding value of  $I^2t$ .



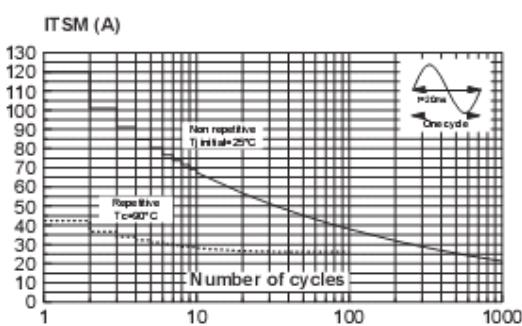
**Fig. 8-1:** Relative variation of critical rate of decrease of main current versus  $(dV/dt)_c$  (typical values) (BW/CW/T1235).



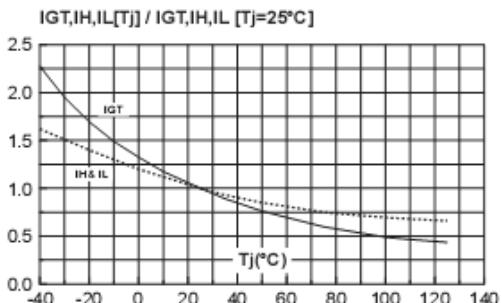
**Fig. 3:** Relative variation of thermal impedance versus pulse duration.



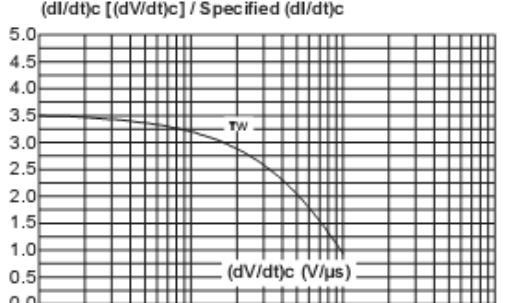
**Fig. 5:** Surge peak on-state current versus number of cycles.



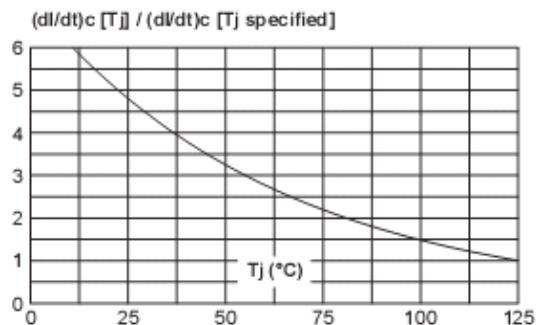
**Fig. 7:** Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).



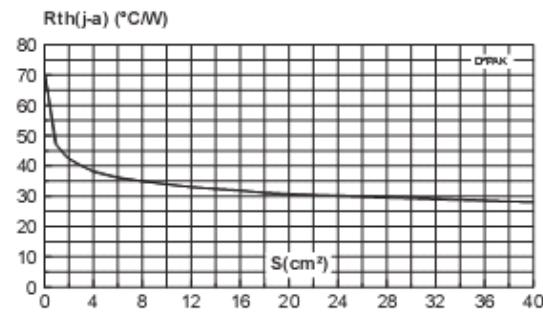
**Fig. 8-2:** Relative variation of critical rate of decrease of main current versus  $(dV/dt)_c$  (typical values) (TW).



**Fig. 9:** Relative variation of critical rate of decrease of main current versus junction temperature.



**Fig. 10:** D<sup>2</sup>PAK Thermal resistance junction to ambient versus copper surface under tab (printed circuit board FR4, copper thickness: 35 µm).



## Package Mechanical Data

